

JOM Call for papers

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The Thin Films and Interfaces Committee is seeking papers on the topic of
Advanced Characterization of Interfaces and Thin Films

Interfaces play an important role in modifying materials properties: structural, electronic, optical and magnetic, etc. The focus of this topic is the advanced characterization of materials interfaces at atomic and nanoscales in metal, alloys, ceramics and polymers by various in situ and ex situ experimental techniques such as raman spectroscopy, x-ray and neutron diffraction, scanning electron microscopy, transmission electron microscopy, and atomic force microscopy (AFM). This topic also involves the understanding of materials interfaces by theoretical modeling approaches that allow the study of these processes on the atomic and molecular levels.

Typical paper length is 5,000 to 6,500 words for review papers, and 2,400 to 4,000 words for original papers.

Detailed author instructions are available at:

<http://www.tms.org/AuthorTools/>

Guest Editors for this *JOM* topic are
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If you are interested in submitting a paper, upload your manuscript at
<https://www.editorialmanager.com/jomj/>

Please note that all submissions will be subject to peer review.
Submission does not guarantee acceptance.

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